



61st ARFTG Microwave Measurements Conference

Measurement Accuracy

IEEE MTT-S IMS2003, Philadelphia, Pennsylvania – June 13, 2003

Conference Organization

Conference Chair

Charles Wilker - DuPont Superconductivity
Chestnut Run Plaza C708/243
Wilmington, DE 19880
302-999-3075, 302-999-2928 (Fax)
charles.wilker@usa.dupont.com

Technical Program Chair:

John W. Cable - Kansas City Plant
(Operated by Honeywell FM&T)
2000 E. 95th St.
Kansas City, MO 64146
816-997-4361
jcable@kcp.com

Exhibits Chair:

Leonard Hayden - Cascade Microtech, Inc.
2430 NW 206th Ave., Beaverton, OR 97006
503-601-1580; 503-601-1601 (Fax)
leonard@micro.com

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DuPont Superconductivity

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Maxim Integrated Products

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Agilent Technologies

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FIRST CALL FOR PAPERS

In conjunction with the IEEE International Microwave Symposium, the Automatic RF Techniques Group will hold its 61st Conference at the Pennsylvania Convention Center, Philadelphia, Pennsylvania on **Friday June 13, 2003**. The conference theme is "Measurement Accuracy."

Join us in exploring cutting-edge microwave measurements for the industrial, academic, and government-related engineering communities. We encourage submissions demonstrating your approach to measurement accuracy and test capabilities at microwave frequencies in these areas:

- Measurements for RF and satellite communication systems
- Measurements for 40 GB/s systems
- Differential measurements
- Traceability to national standards labs
- Models for measurement verification
- Vector network analysis
- Large-signal network analysis
- Power and noise
- On-wafer measurements

Papers are also invited in other areas automated microwave and RF measurements.

DEADLINES

March 7, 2003

Electronic Abstract/Summary due to papersubmission@arftg.org

April 11, 2003

Publication-ready paper due in pdf format to papersubmission@arftg.org

Paper acceptance and classification will be communicated by **March 14, 2003**. If your paper is accepted, you are invited to submit to the Special Transactions Symposium Issue of IEEE MTT.

INSTRUCTIONS FOR AUTHORS

Contributed papers will be presented as 20-minute talks or in an interactive poster session, and published in both the 61st ARFTG Digest and the 2003 International Microwave Symposium CD-ROM. You can express a preference for an interactive poster session.

We request that authors submit a one-page abstract and a 500-1000 word summary, including illustrations, to allow for evaluation with regard to the interests of the participants and the quality and novelty of the work. Please make your submission electronically to the email submission address listed above following the *Abstracts/Summary Submission Instructions* found on the web site, www.arftg.org.

EXHIBITS

The 61st ARFTG Conference also offers an outstanding exhibition opportunity. Please contact our Exhibits Chair directly for further information.



www.arftg.org

